

Nickel-chromium thin film - Depth profile

Art. ID	NIST-2135c
Unit	each
Deliverydetails	No Dangerous Good /not restricted

Description

This Standard Reference Material (SRM®) is intended primarily for calibrating sputtered depth scales and erosion rates in surface analysis. Its periodic structure, consisting of eight well-defined metal/metal interfaces, can be used to obtain accurate calibration at a number of depths. NIST-2135c is certified for total Chromium (Cr) and Nickel (Ni) thickness, single element layer-to-layer uniformity, Ni and Cr bilayer uniformity (periodicity) and single layer thickness. /// Sample value(s) - please ask for current certificate.

Text/Information	Analyte/Parameter	CAS number	Concentration/Value	Unit	Method	Source
Cr	Total Thickness		206,3 ± 13,8	µg/cm ²		
Ni	Total Thickness		197,4 ± 9,6	µg/cm ²		
Single Cr Layer	Layer-to-Layer Uniformity		0,8	%		
Single Ni Layer	Layer-to-Layer Uniformity		0,9	%		
Bilayer	Layer-to-Layer Uniformity		0,6	%		
Cr	Single Layer Thickness		41,3 ± 2,8	µg/cm ²		
Ni	Single Layer Thickness		49,4 ± 2,6	µg/cm ²		